Wuxi Unigroup Microelectronics Company

500V Super-junction Power MOSFET

Description

500V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs，designed according to the SJ principle. The deep trench SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

Features

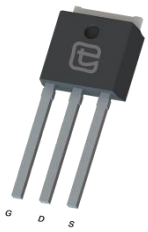
- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- Easy to use/drive
- RoHS compliant

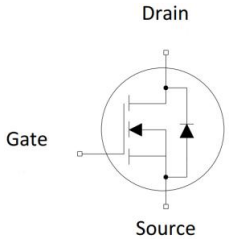
Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- Charger

TO-252

TO-251





RoHS

Device Marking and Package Information

Device	Package	Marking
TPD50R1K5CT	TO-252	50R1K5CT
TPU50R1K5CT	TO-251	50R1K5CT

Key Performance Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j,max}$	550	V
$R_{DS(on),max}$	1.5	Ω
$Q_{g,typ}$	5.3	nC
I_D	2	A
$I_{D,pulse}$	6	A

Absolute Maximum Ratings T_C = 25ºC, unless otherwise noted				
Parameter		**Symbol**	**Values**	**Unit**
Continuous Drain Current	T_C = 25ºC	I_D	2	A
Pulsed Drain Current	(note1)	$I_{D,pulse}$	6	A
Gate-Source Voltage		V_{GSS}	±30V	V
Single Pulse Avalanche Energy	(note2)	E_{AS}	12	mJ
Repetitive Avalanche Energy	(note2)	E_{AR}	0.05	mJ
Avalanche Current		I_{AR}	0.5	A
Power Dissipation For TO-252,TO-251		P_D	17.8	W
Continuous Diode Forward Current		I_S	2	A
Diode Pulsed Current	(note1)	$I_{S,pulse}$	6	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55~+150	ºC

Thermal Resistance For TO-252,TO-251			
Parameter	**Symbol**	**Value**	**Unit**
Thermal Resistance, Junction-to-Case	R_{thJC}	7.0	ºC/W
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62	

Specifications T_J = 25ºC, unless otherwise noted						
Parameter	**Symbol**	**Test Conditions**	**Value**			**Unit**
			Min.	**Typ.**	**Max.**	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0V, I_D = 250μA	500	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 500V, V_{GS} = 0V, T_J = 25ºC	--	--	1	μA
		V_{DS} = 500V, V_{GS} = 0V, T_J = 150ºC	--	--	100	
Gate-Source Leakage	I_{GSS}	V_{GS} = ±30V	--	--	±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250μA	1.1	--	2.5	V
Drain-Source On-Resistance (Note3)	$R_{DS(on)}$	V_{GS} = 10V, I_D = 1A	--	1.3	1.5	Ω
Forward Transconductance (Note3)	g_{fs}	V_{DS} = 10V, I_D = 1A	--	2	--	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0V, V_{DS} = 50V, f = 1.0MHz	--	174	--	pF
Output Capacitance	C_{oss}		--	10	--	
Reverse Transfer Capacitance	C_{rss}		--	1.5	--	
Total Gate Charge	Q_g	V_{DD} = 480V, I_D = 2A, V_{GS} = 10V	--	5.3	--	nC
Gate-Source Charge	Q_{gs}		--	1	--	
Gate-Drain Charge	Q_{gd}		--	2.7	--	
Turn-on Delay Time	$t_{d(on)}$	V_{DD} = 400V, I_D = 2A, R_G = 25Ω	--	30	--	ns
Turn-on Rise Time	t_r		--	29	--	
Turn-off Delay Time	$t_{d(off)}$		--	54	--	
Turn-off Fall Time	t_f		--	31	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	T_C = 25ºC	--	--	2	A
Pulsed Diode Forward Current	I_{SM}		--	--	6	
Body Diode Voltage	V_{SD}	T_J = 25ºC, I_{SD} = 2A, V_{GS} = 0V	--	0.9	1.2	V
Reverse Recovery Time	t_{rr}	V_R = 480V, I_F = I_S, di_F/dt = 100A/μs	--	150	--	ns
Reverse Recovery Charge	Q_{rr}		--	0.5	--	μC
Peak Reverse Recovery Current	I_{rrm}		--	6.0	--	A

Notes

1. Repetitive Rating: Pulse Width limited by maximum junction temperature
2. I_{AS} = 1.5A, V_{DD} = 50V, R_G = 25Ω, Starting T_J = 25°C
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 1%

Typical Characteristics T_J = 25ºC, unless otherwise noted

Figure 1. Output Characteristics

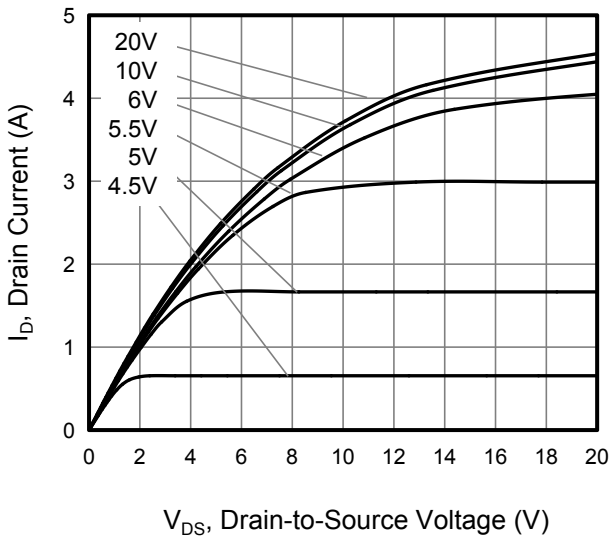


Figure 2. Transfer Characteristics

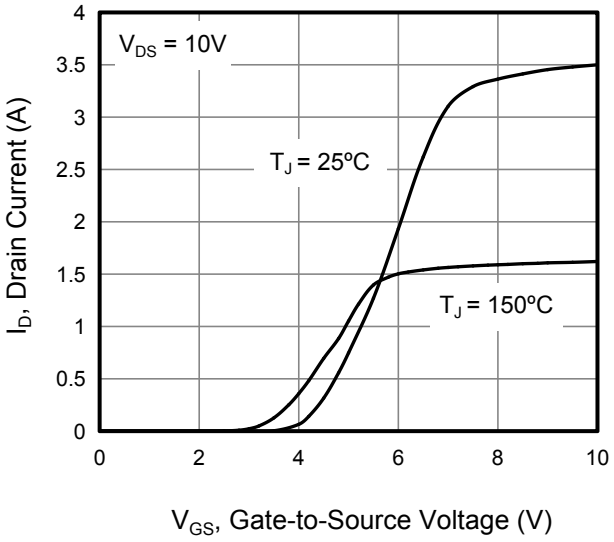


Figure 3. On-Resistance vs. Drain Current

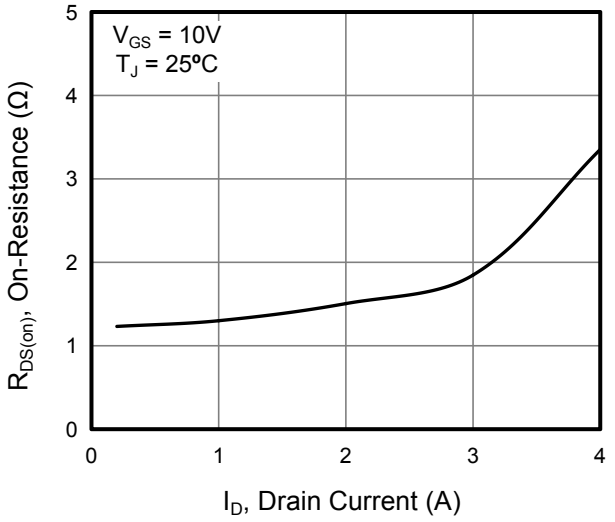


Figure 4. Capacitance

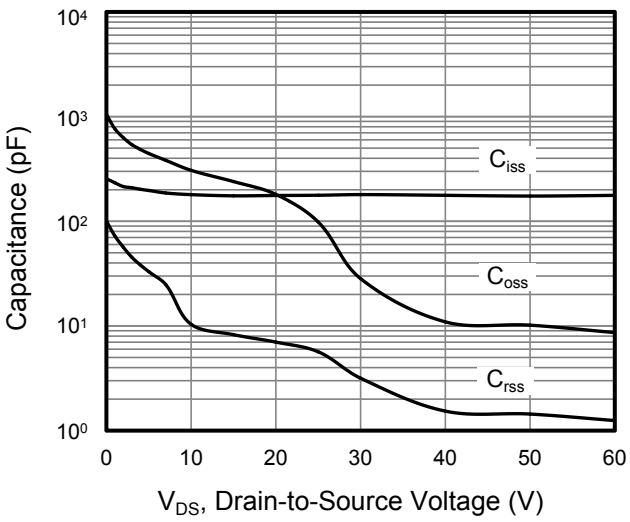


Figure 5. Gate Charge

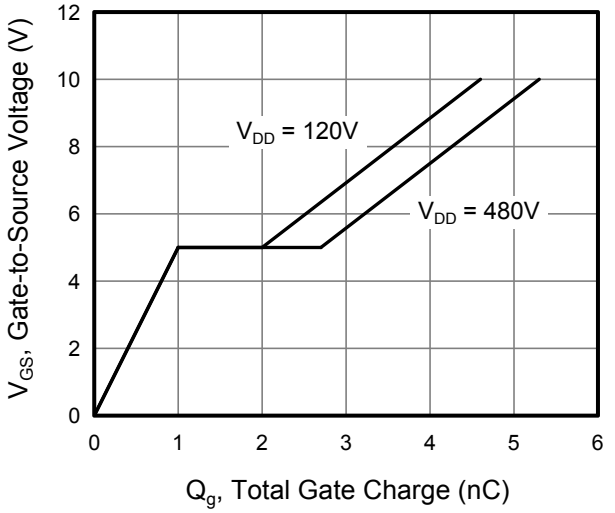
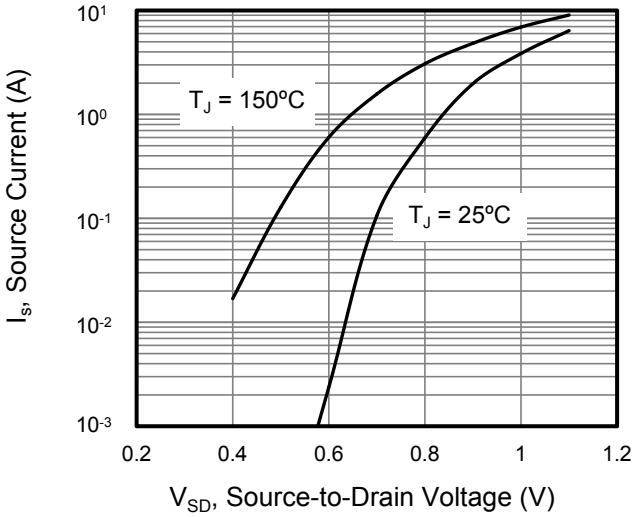


Figure 6. Body Diode Forward Voltage



Typical Characteristics T_J = 25ºC, unless otherwise noted

Figure 7. On-Resistance vs. Junction Temperature

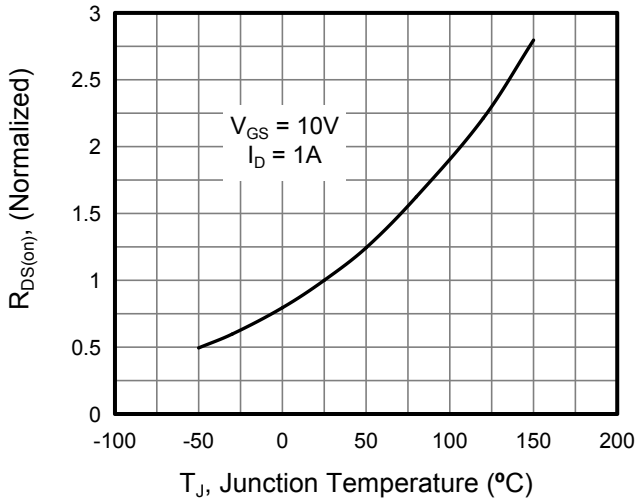


Figure 8. Threshold Voltage vs. Junction Temperature

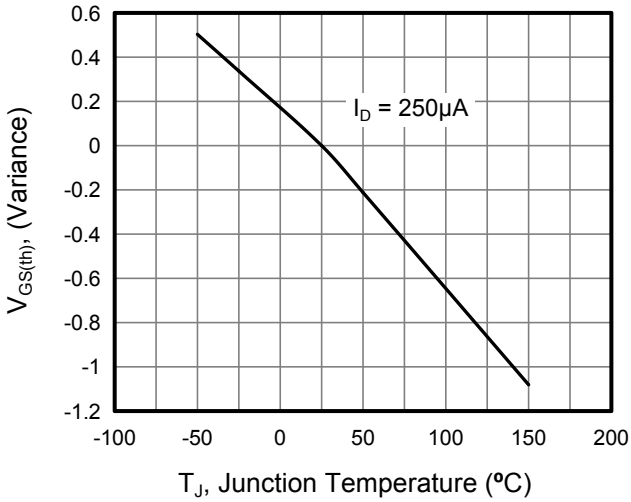


Figure 9. Transient Thermal Impedance TO-251/TO-252

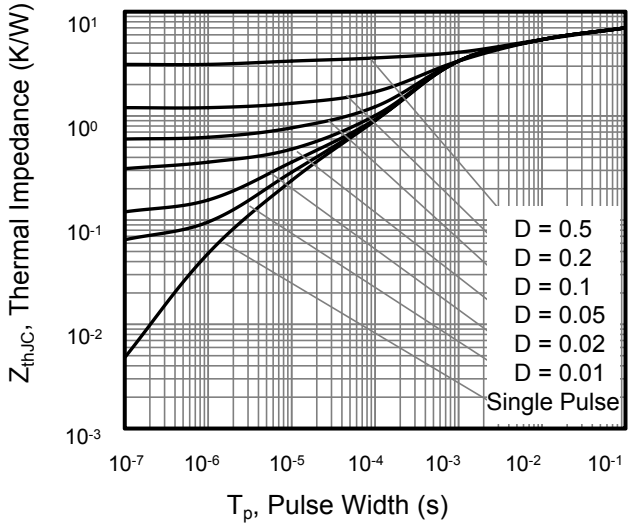


Figure 10. Safe Operation Area For TO-252/TO-251

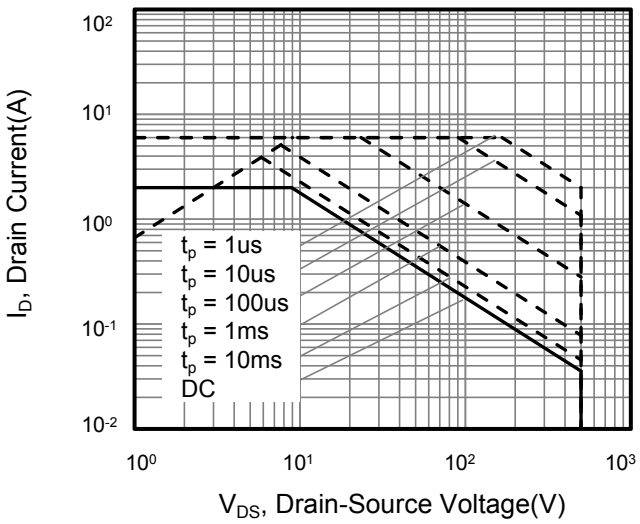


Figure A：Gate Charge Test Circuit and Waveform

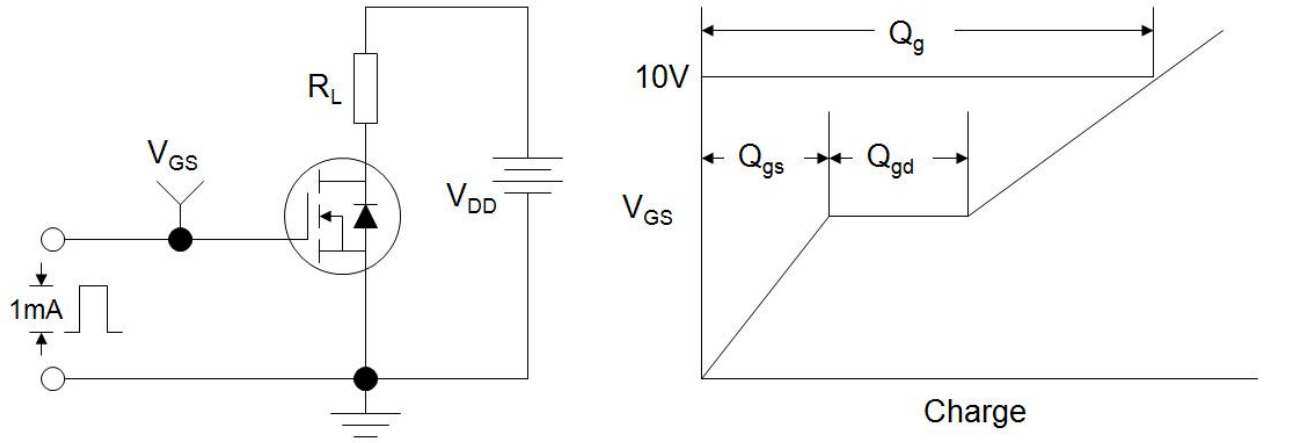


Figure B：Resistive Switching Test Circuit and Waveform

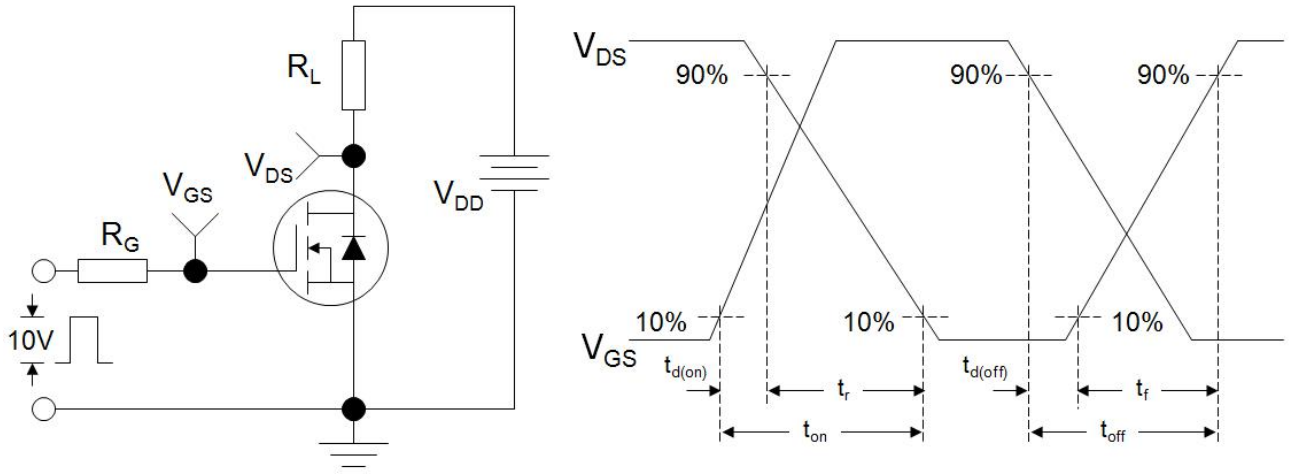
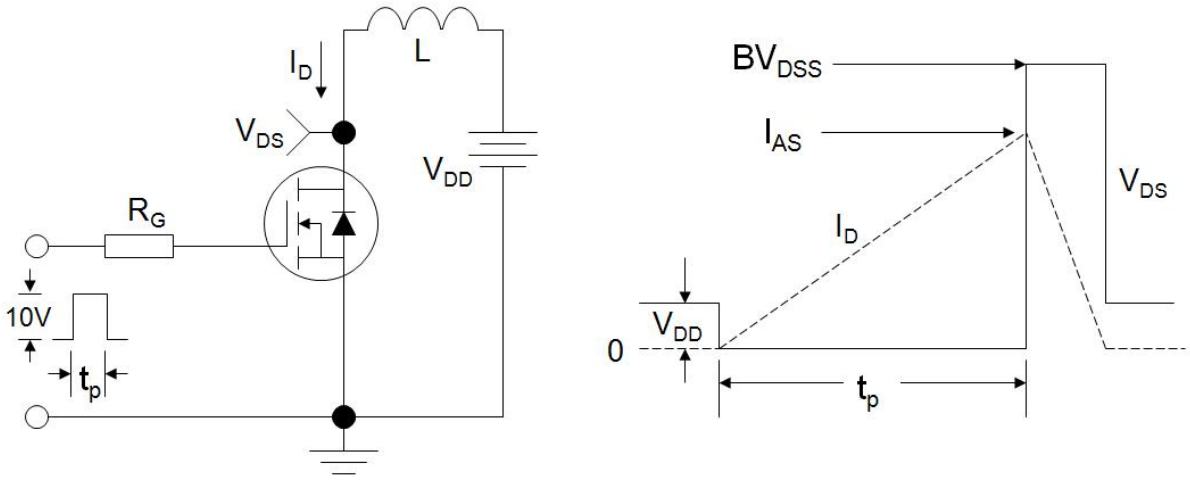
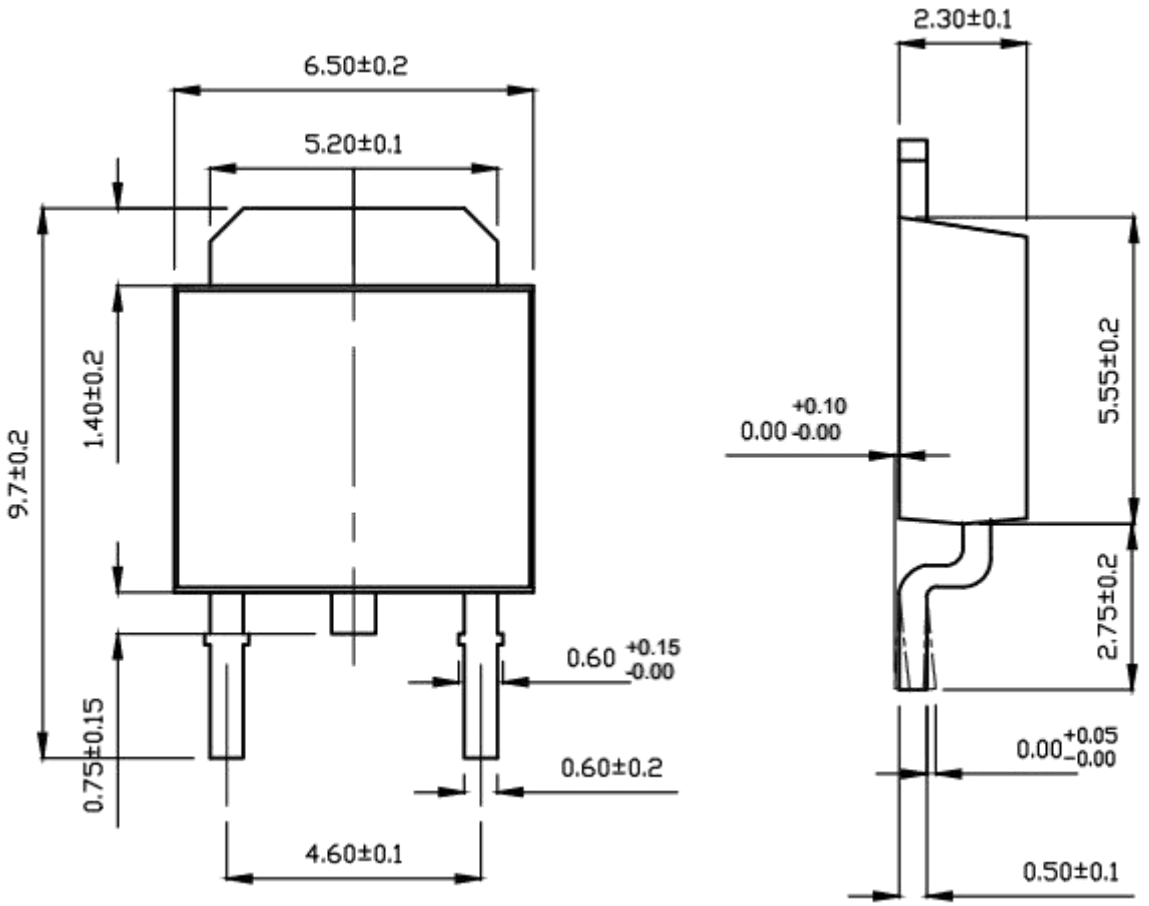


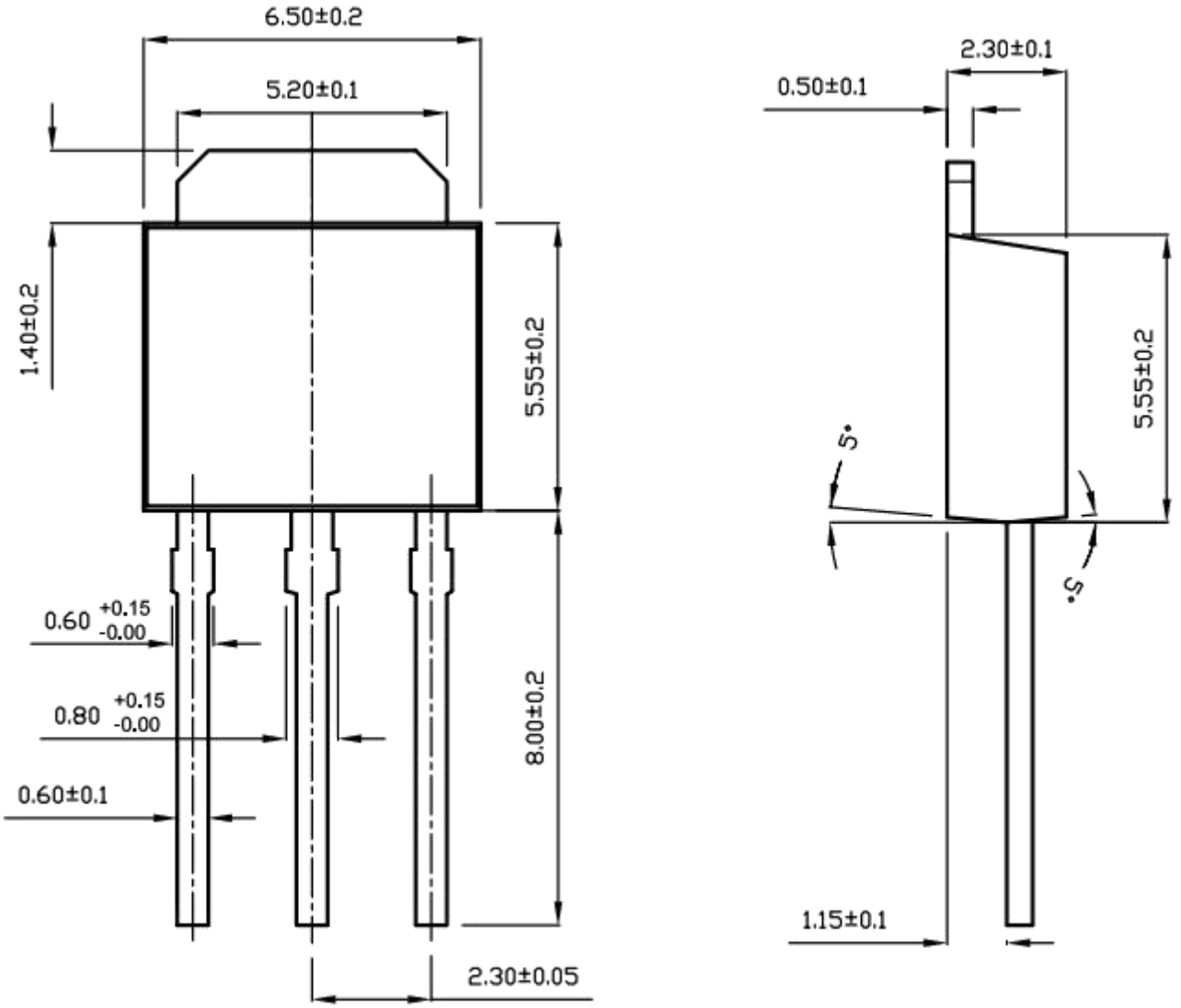
Figure C：Unclamped Inductive Switching Test Circuit and Waveform



TO-252（封装厂 C）


6.50±0.2
5.20±0.1
1.40±0.2
9.7±0.2
0.75±0.15
0.60 +0.15 -0.00
0.60±0.2
4.60±0.1
2.30±0.1
0.00 +0.10 -0.00
5.55±0.2
2.75±0.2
0.00 +0.05 -0.00
0.50±0.1

TO-251（封装厂 C）


6.50±0.2
5.20±0.1
1.40±0.2
5.55±0.2
0.60 +0.15 -0.00
0.80 +0.15 -0.00
0.60±0.1
8.00±0.2
2.30±0.05
2.30±0.1
0.50±0.1
5.55±0.2
5°
5°
1.15±0.1

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